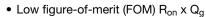


DTP15N50SJ-VB Datasheet

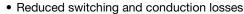
N-Channel 500V (D-S)Super Junction Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V) at T _J max.	500				
R _{DS(on)} at 25 °C (Ω)	V _{GS} = 10 V	0.29			
Q _g max. (nC)	38				
Q _{gs} (nC)	5				
Q _{gd} (nC)	22				
Configuration	Single				

FEATURES



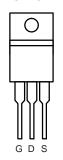




- Ultra low gate charge (Q_q)
- Avalanche energy rated (UIS)

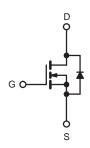
APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial



TO-220AB





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	500		
Gate-Source Voltage			V_{GS}	± 30	V	
Continuous Drain Current /T 150 °C\	\/ at 10.\/	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	C I _D	15		
Continuous Drain Current (T _J = 150 °C)	V _{GS} at 10 V	T _C = 100 °C		9.4	Α	
Pulsed Drain Current ^a			I _{DM}	45		
Linear Derating Factor				3.6	W/°C	
Single Pulse Avalanche Energy b			E _{AS}	9	mJ	
Maximum Power Dissipation			P_{D}	156/34	W	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C	
Drain-Source Voltage Slope	T _J = 125 °C		-I) //-I±	15	N//	
Reverse Diode dV/dt ^d			dV/dt	4.1	V/ns	
Soldering Recommendations (Peak Temperature) c	emperature) c for 10 s			300	°C	

- a. Repetitive rating; pulse width limited by maximum junction temperature. b. V_{DD} = 50 V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 4.5 A.
- c. 1.6 mm from case.
- d. $I_{SD} \le I_D$, dI/dt = 100 A/ μ s, starting $T_J = 25$ °C.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	60	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.8	C/VV		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							•
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		500	-	-	٧
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.75	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		2	-	4	٧
	$V_{GS} = \pm 20 \text{ V}$		V _{GS} = ± 20 V	-	-	± 100	nA
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 30 V		-	-	± 1	μA
		V _{DS} = 500 V, V _{GS} = 0 V		-	-	1	
Zero Gate Voltage Drain Current	I _{DSS}		/, V _{GS} = 0 V, T _J = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 8 A	-	0.29	-	Ω
Forward Transconductance	9fs	V _{DS}	s = 30 V, I _D = 8 A	-	16	-	S
Dynamic		,					•
Input Capacitance	C _{iss}		V _{GS} = 0 V,	-	800	-	
Output Capacitance	Coss	1	$V_{DS} = 100 \text{ V},$	-	70	-	
Reverse Transfer Capacitance	C _{rss}	f = 1 MHz		-	8	-	pF
Effective Output Capacitance, Energy Related ^a	C _{o(er)}	V _{DS} = 0 V to 400 V, V _{GS} = 0 V		-	63	-	
Effective Output Capacitance, Time Related ^b	C _{o(tr)}			-	213	-	
Total Gate Charge	Qg			-	48	96	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 8 \text{ A}, V_{DS} = 400 \text{ V}$		-	11	-	nC
Gate-Drain Charge	Q_{gd}			-	21	-	<u> </u>
Turn-On Delay Time	t _{d(on)}	V _{DD} = 400 V, I _D = 8 A,		-	13	25	
Rise Time	t _r			-	11	35	ns
Turn-Off Delay Time	$t_{d(off)}$		$V_{GS} = 10 \text{ V}, R_g = 9.1 \Omega$		81	90	
Fall Time	t _f				25	40	
Gate Input Resistance	R_{g}	f = 1 MHz, open drain		-	3.5	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	15	
Pulsed Diode Forward Current	I _{SM}			-	-	40	- A
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 8 A, V _{GS} = 0 V		-	-	1.5	V
Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = I _S = 8 A, dl/dt = 100 A/μs, V _R = 400 V		-	345	-	ns
Reverse Recovery Charge	Q _{rr}			-	4.5	-	μC
Reverse Recovery Current	I _{RBM}			_	35	_	A

Notes

- a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

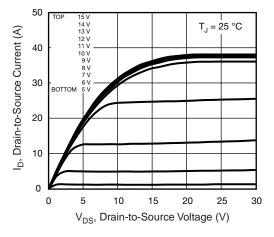


Fig. 1 - Typical Output Characteristics

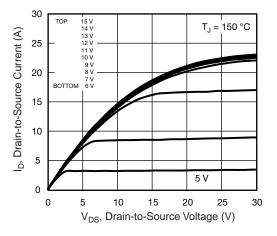


Fig. 2 - Typical Output Characteristics

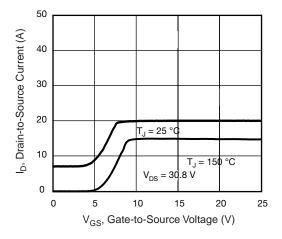


Fig. 3 - Typical Transfer Characteristics

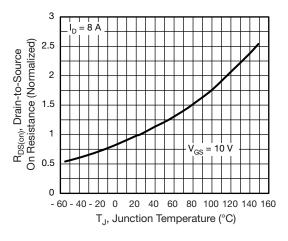


Fig. 4 - Normalized On-Resistance vs. Temperature

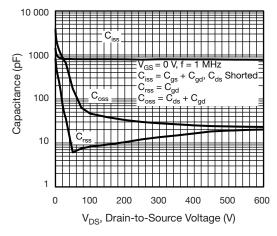


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

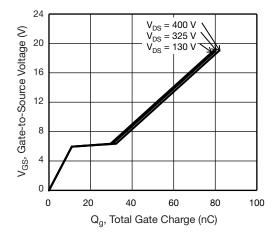


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



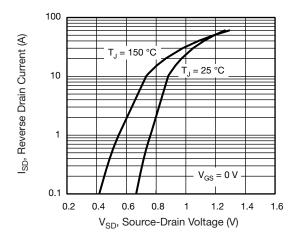


Fig. 7 - Typical Source-Drain Diode Forward Voltage

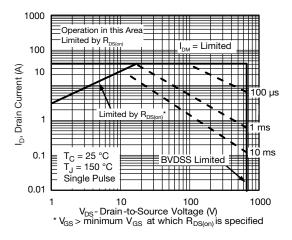


Fig. 8 - Maximum Safe Operating Area

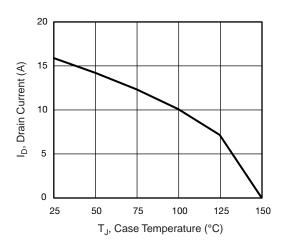


Fig. 9 - Maximum Drain Current vs. Case Temperature

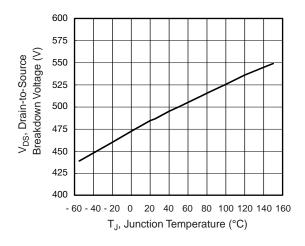


Fig. 10 - Temperature vs. Drain-to-Source Voltage

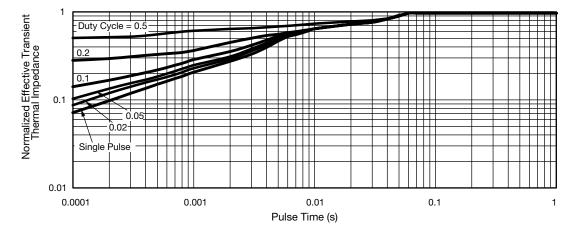


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



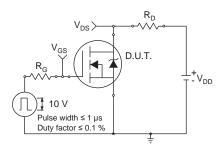


Fig. 12 - Switching Time Test Circuit

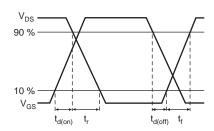


Fig. 13 - Switching Time Waveforms

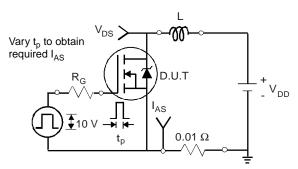


Fig. 14 - Unclamped Inductive Test Circuit

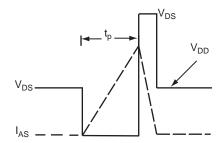


Fig. 15 - Unclamped Inductive Waveforms

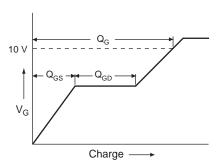


Fig. 16 - Basic Gate Charge Waveform

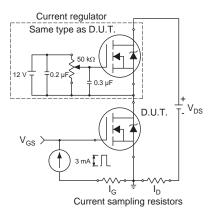
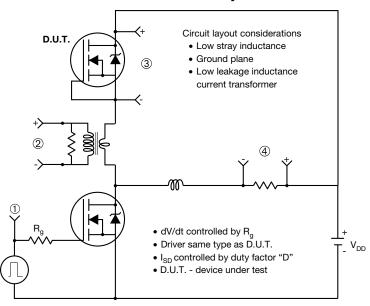


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



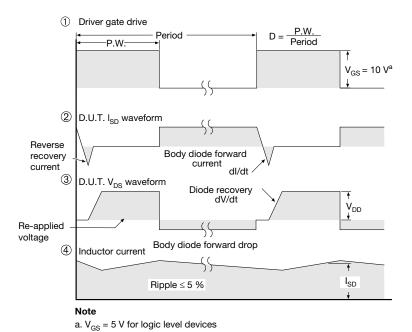
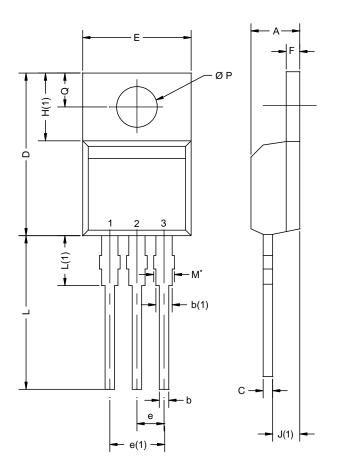


Fig. 18 - For N-Channel



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	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

Notes

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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